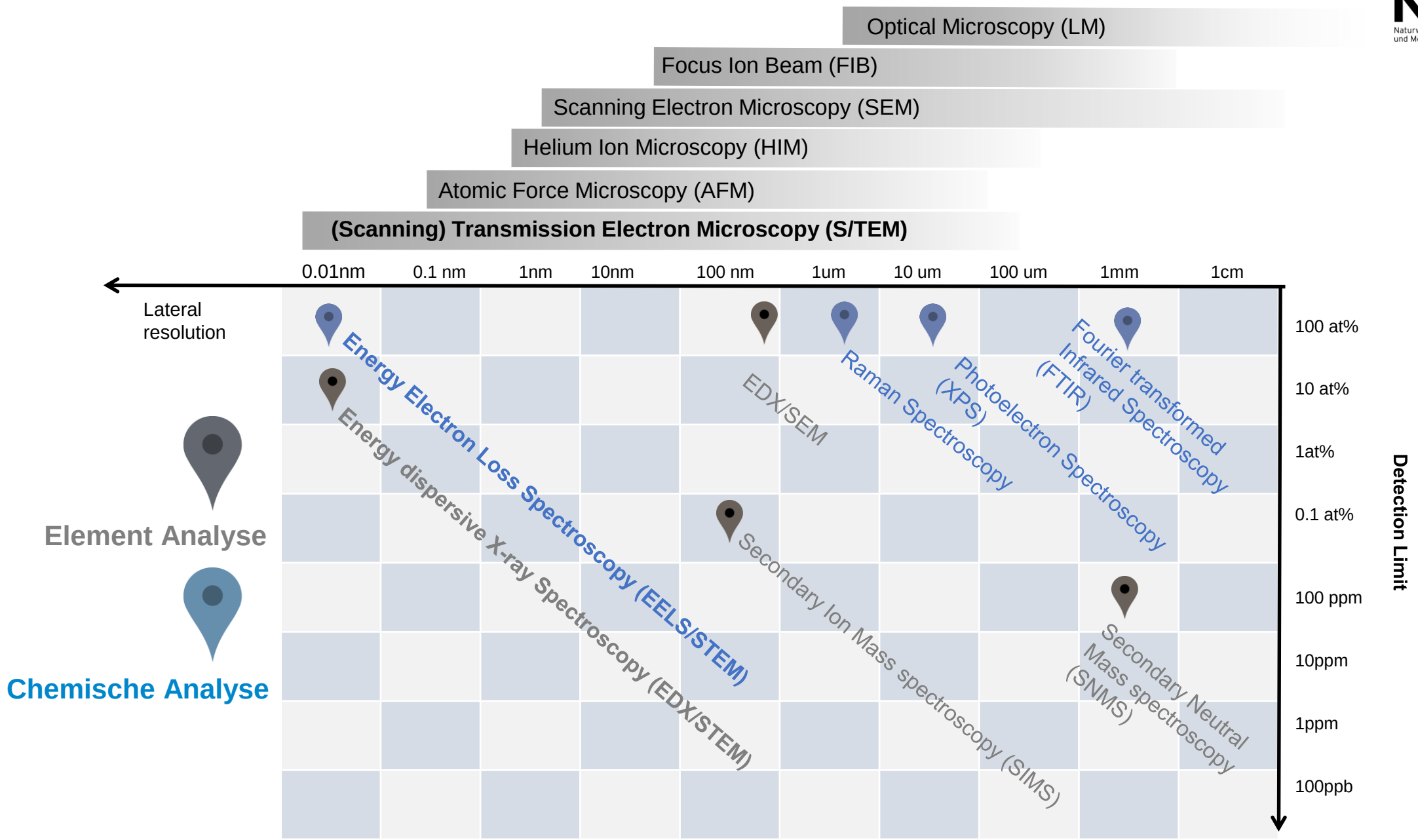
Optical Microscopy (LM)
Focus Ion Beam (FIB)
Scanning Electron Microscopy (SEM)
Helium Ion Microscopy (HIM)
Atomic Force Microscopy (AFM)
(Scanning) Transmission Electron Microscopy (S/TEM)
0.01nm
0.1 nm
1nm
10nm
100 nm
1um
10 um
100 um
1mm
1cm
Lateral resolution
Energy Electron Loss Spectroscopy (EELS/STEM)
Energy dispersive X-ray Spectroscopy (EDX/STEM)
EDX/SEM
Raman Spectroscopy
Photoelectron Spectroscopy (XPS)
Fourier transformed Infrared Spectroscopy (FTIR)
Secondary Ion Mass spectroscopy (SIMS)
Secondary Neutral Mass spectroscopy (SNMS)
Element Analyse
Chemische Analyse
100 at%
10 at%
1at%
0.1 at%
100 ppm
10ppm
1ppm
100ppb
Detection Limit